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		5,006,913	4-9-91	Sugabar	a, et al.			1	
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		5,081,513	1-14-92	Jackson,	et al.		1	<del>                                     </del>	
t		5,108,843	4-28-92	Ohtaka,	et al.	1	<b>†</b>	1	
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V		US 2003/0040158 A1	2-27-03	Saltoh	······································				
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Þ		Gregory Scott, et al., "NA International Electron De	10S Drive Curret vices Meeting, 34.	t Reduction 4.1, IEEE,	C11 85	Layout and Tr	ench Isolation	Induced	Strem."
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		US 2003/0067035 A1	4-10-03	Tews, et s	a <b>l,</b>				
		US 2004/0113174 A1	6-17-2004	Chidamba	urao et al.				
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P		International Electron De	vices Meeding, 10	.7.1 <b>, ieee</b> ,	April 2000.				
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		International Electron De	vices Meeting, IE	EE, March	2001.				
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		5,670,798	9-23-97	Schetzin	a	<del> </del>	1	<del>                                     </del>	· · · · · · · · · · · · · · · · · · ·
		5,679,965	10-21-97	Schetzin	1	<b>†</b>		<del>                                     </del>	
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		6,255,169	7-3-01	Li, et al.			·			
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		6,265,317	7-24-01	Chiu, et	al.				<del></del>	
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		J.W. Matthews, et al (1974), pp. 118-125.	., "Defects i	in Epitar	ial Multilayers". J	ournal of	Crystal Gro	owth 27		
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		6,284,623	9-4-01	Zhang, e	t al.				
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19		IEEE Transactions	on wection De	evices, Vo	ol. 36, No. 10, Oct	ober 1989,	pp. 2043-2	064.	
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		6,483,171	11-19-02	Forbes, e	et al.					
		6,493,497	12-1 <del>0-0</del> 2	Ramdani	l, et al.	·			<del></del>	
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1		7,015,082	3-21-2006	Doris e	et al.					
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1		6,977,194	12-20-2005	Belyansk	sy et al.					
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